

# **Preface**

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# **PREFACE**

The seventh symposium on Atomic Layer Deposition Applications was held October 10 through 12, 2011 in Boston, Massachusetts, as part of the 220<sup>th</sup> Meeting of the Electrochemical Society.

The focus of this symposium is the continuously expanding realm of Atomic Layer Deposition (ALD) applications. ALD allows the precise deposition of ultrathin, highly conformal coatings over complex, 3D topographies with controlled composition and properties. In its 7<sup>th</sup> successful year, this symposium has become a forum for sharing cutting edge research in the various technologies where ALD is currently used. Emerging and non-mainstream ALD applications are also of special interest.

This issue of the *ECS Transactions* contains 36 peer reviewed papers presented at the symposium. The papers are organized into Chapters generally following the order and structure of the symposium sessions. Featured ALD topics include ALD for photovoltaics, ALD for batteries and fuel cells, dielectrics for state-of-the-art transistors and capacitors, and the ALD of metals and metal nitrides. A number of papers report on advances in ALD precursor and equipment development, and in particular the continued progress in high throughput ALD equipment.

We wish to thank the invited speakers for their outstanding contributions: Ivo Raaijmakers, ASM International, Soo-Hyun Kim, Yeungnam University, Johan Swerts, IMEC, Kornelius Nielsch, University of Hamburg, Fritz Prinz, Stanford University, Titta Aaltonen, University of Oslo, Jane Chang, University of California, Simon Elliott, Tyndall National Institute, Christian Wenger, IHP, Jacques Kools, Encapsulix SAS, Thomas Proslier, Argonne National Laboratory, Byunghoon Yoon, University of Colorado, Gijs Dingemans, Technische Universiteit Eindhoven, Nicolas Tetreault, Ecole Polytechnique Federale de Lausanne

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